

# **Application Note AN077**

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# **RF** and **Protection Devices**

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<b>Application N</b>	ote AN077				
Revision History: 2013-10-01					
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Page	Subjects (major changes since last revision)				
All	This Application Note replaces the revision from 2007-01-08.				
All	The AN has been revised completely.				

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### **Thermal Resistance Definition**

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**Thermal Resistance Definition** 

# 1 Thermal Resistance Definition

A thermal equivalent circuit is a behavior model to describe the heat transportation between various locations. A static thermal equivalent circuit is analog to an electrical circuit. A static thermal equivalent circuit usually consists of the following elements:

- heat source  $P_v$  (analog to current source in a electrical circuit), where the heat is generated with the unit watt (W),

- temperature T (analog to the potential in a electrical circuit) with the unit Kelvin (K),

- thermal resistance  $R_{th}$  (analog to ohmic resistance in a electrical circuit) with the unit (K/W).

The thermal resistance describes the thermal conductivity of a thermal media between two locations.

**Figure 1** shows a static thermal equivalent circuit that heat  $P_V$  is generated in a thermal conductive material (represented by its temperature of  $T_j$  and thermal resistance  $R_{th}$ ) and dissperted to the environment with ambient temperature of  $T_a$ . The relationship between the elements can be written as following:

$$T_J - T_A = P_V \cdot R_{th}$$



Figure 1 Static Thermal Equivalent Circuit



# 2 Thermal Resistance of Transistors and Diodes in SMD Packages

**Figure 2** shows a general thermal case for packaged devices such as transistors and diodes soldered on PCB. The heat caused by the power dissipation  $P_{tot}$  in the active region of a semiconductor device during operation results in an increased temperature of the component. A general equivalent circuit is presented by **Figure 3**.



Figure 2 Gull-wing (or J-lead) Package on Substrate (e.g. PCB)



Figure 3 Static Equivalent Circuit of Thermal Resistance



### Thermal Resistance of Transistors and Diodes in SMD Packages

The heat is conducted from its source (junction J or channel Ch) through the chip, along the package leadframes, the soldering Point S and through the substrate (PCB) to the heat sink (ambient A). The junction temperature  $T_J$  for a given ambient temperature  $T_A$  is determined by the thermal resistance  $R_{thJA}$  and the power dissipation  $P_{tot}$ 

$$T_{\rm J} = T_{\rm A} + P_{\rm tot} * R_{\rm thJA}$$

(with R<sub>thJA</sub> in K/W or °C/W)

In SMD packages the heat is primarily conducted via the leads to the external pins respectively soldering points. The total thermal resistance consists of the following components:

$$R$$
thJA =  $R$ thJS +  $R$ thSA

with

RthJS = RthJB + RthBS

Table 1 A	bbreviations of	Thermal	Resistances
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<b>R</b> thJA	Thermal resistance between junction and ambient (total thermal resistance)
<i>R</i> thJS	Thermal resistance between junction and soldering point (e.g. footprint on PCB)
<i>R</i> <sub>th</sub> JB	Thermal resistance between junction and chip backside (chip thermal resistance)
R <sub>th</sub> BS	Thermal resistance between chip backside and soldering point (package thermal resistance)
<b>R</b> t <sub>h</sub> SA	Thermal resistance between soldering point and ambient (substrate thermal resistance)

 $R_{th}$ JS contains all device internal thermal resistances. Knowing  $R_{th}$ JS it is possible to calculate the junction respectively channel temperature  $T_J$  for a given power dissipation  $P_{tot}$  and soldering point temperature  $T_S$ .  $T_S$  is the temperature of the hottest soldering point that is measured at the lead on which the chip is assembled.

$$T_J = T_S + P_{tot \times} R_{thJS}$$

The temperature of the soldering point  $T_S$  in turn depends on the dissipated power  $P_{tot}$ , the ambient temperature  $T_A$  and the thermal resistance  $R_{thSA}$  of the pc board (substrate).

$$T_{\rm S} = T_{\rm A} + P_{\rm tot} * R_{\rm thSA}$$

hence

$$T_{\rm J} = T_{\rm A} + P_{\rm tot} * (R_{\rm thJS} + R_{\rm thSA})$$



In product datasheets only the  $R_{thJS}$  value can be stated, since only this part of the total thermal resistance  $R_{thJA}$  is controlled by the device manufacturer.

Estimated  $R_{thSA}$  values for different substrate materials as a function of the area of the mounting pad respectively substrate can be found in the both diagrams below, the parameter is ( $T_S$ - $T_A$ ). Depending on the application, various substrates such as FR4, Rogers, LTCC and Alumina are used. In consumer and wireless applications, FR4 is the major material used as PCB material. It composites several layers of copper and glass-reinforced polymer stacked. FR4 material usually has thermal resistance in the range of 250 to 300 K/W, depending on the total thickness of copper and the via hole placement between the layers (**Figure 4**).



Figure 4 Estimated thermal resistance between soldering point and ambient for a typical PCB



## 2.1 Permissible Total Power Dissipation in Continuous Operation

In the maximum ratings section of product datasheets the maximum permissible total power dissipation  $P_{totmax}$  is specified.  $P_{totmax}$  may only be applied if the maximum junction or channel temperature  $T_{Jmax}$  is not exceeded. Otherwise the allowable power dissipation  $P_{tot}$  has to be reduced, as shown in a so called derating curve. In the example of **Figure 5** up to a soldering point temperature  $T_{Smax}$  of 94 °C the maximum permissible total power dissipation  $P_{totmax}$  may be applied, in this case 600 mW. The junction temperature  $T_J$  is then lower than  $T_{Jmax}$ , which is often 150 °C for silicon devices. For higher soldering point temperatures  $T_S$  the power dissipation  $P_{tot}$  has to be reduced according to the derating curve, on each point of the declining curve the junction temperature attains its maximum permissible value  $T_{Jmax}$ . The soldering point temperature  $T_S$  where  $P_{tot}$  has to be reduced can be calculated according to

$$T$$
Smax =  $T$ Jmax -  $P$ totmax \*  $R$ thJS

Accordingly the ambient temperature from which the power dissipation  $P_{tot}$  has to be reduced calculates according to

$$T$$
Amax =  $T$ Jmax -  $P$ totmax \*  $R$ thJA

In diodes the power dissipation is mainly caused by internal resistances. So the diagram has to be translated into the form  $I_F = f(T_S; T_A)$ , what results in derating curves with a bent shape, see **Figure 6.** Please regard that the derating curves shown in **Figure 5** and **Figure 6** are examples.





### Thermal Resistance of Transistors and Diodes in SMD Packages

Figure 5 Example for Total Power Dissipation  $P_{tot} = f(T_s; T_A^{(1)})$ 



Figure 6 Example for Forward Current  $I_F = f(T_S; T_A^{(1)})$ 

1) Al<sub>2</sub>O<sub>3</sub>-substrate 15 mm x 16.7 mm x 0.7 mm. Package mounted on aluminum 15 mm x 16.7 mm x 0.7 mm



## 2.2 Permissible Total Power Dissipation in Pulse Operation

In pulse operation under certain circumstances higher total power dissipation can be permitted as in continuous operation. This is the case if the pulse duration  $t_P$ , i.e. the length of time interval where the power is applied, is short compared to the thermal time constant of the system. The thermal time constant, i.e. the time until the static temperature respectively thermal equilibrium is approximately reached, depends on the thermal capacitances and resistances of the component and the substrate. The higher permissible total power dissipation in pulse load operation can also be understood as a smaller thermal resistance. **Figure 7** shows an example of a pulse load thermal resistance versus pulse duration  $t_P$ , **Figure 8** an example for a pulse load permissible total power dissipation (normalized to its continuous value) versus pulse duration  $t_P$ . In these charts T is the duration of a full signal cycle, that is ON + OFF time.

For more detailed information about thermal resistance of semiconductor devices please refer Infineon's online white paper for thermal resistance: <u>Thermal Resistance Theory and</u> <u>Practice</u>.





Figure 7 Pulse Load Thermal Resistance  $R_{\text{thJS}} = f(t_p)$ 



Figure 8 Pulse Load Permissible Total Power Dissipation  $P_{\text{totmax}} / P_{\text{totDC}} = f(t_p)$ 

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